

Search Notes

Application/Control No.

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Examiner

KEVIN L. LEE

Applicant(s)/Patent under
Reexamination

MIKIYA ET AL.

Art Unit

3753

SEARCHED

Class	Subclass	Date	Examiner
UPDATED	SEARCH	4/17/2006	KL

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR